_	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/521,666	BONA ET AL.
	Examiner	Art Unit
	Truc T. T. Nguyen	2833

<u></u>	<del> </del>	· <del></del>			
	SEARCHED				
Class	Subclass	Date	Examiner		
439	172-174 106 222	5/27/2006	TN		
			·		
		\$°			

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
see search	history print	5/27/2006	TN	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
see search history print	5/27/2006	TN			
<u> </u>					
·					